



Reichenbach Engineering



CMOB-2

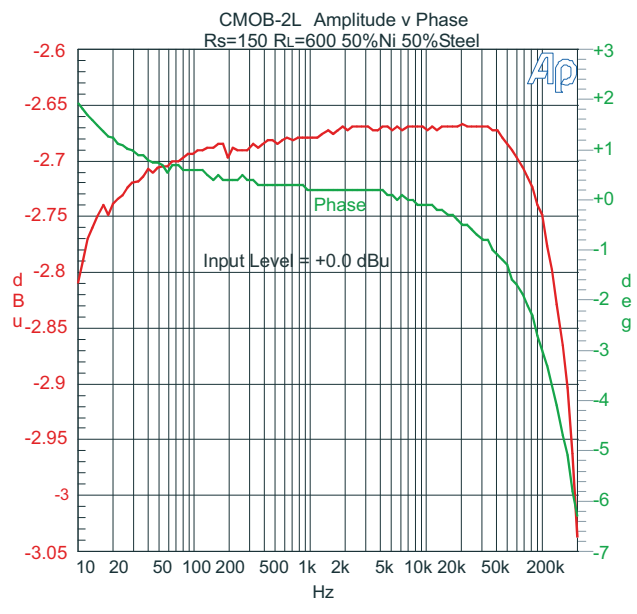
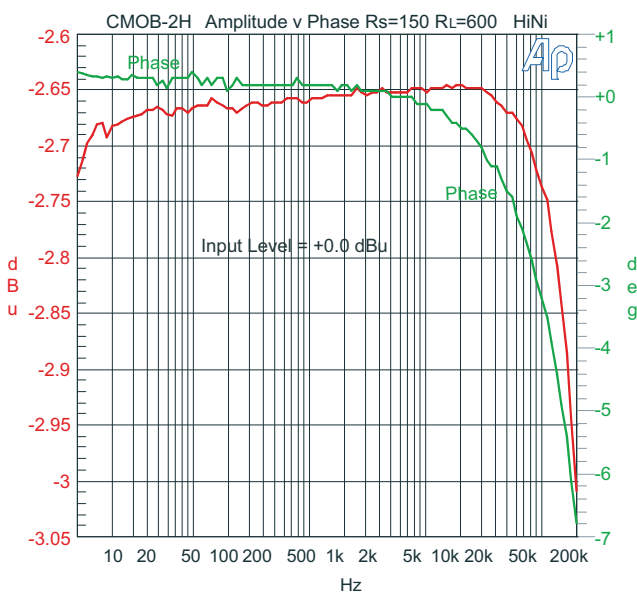
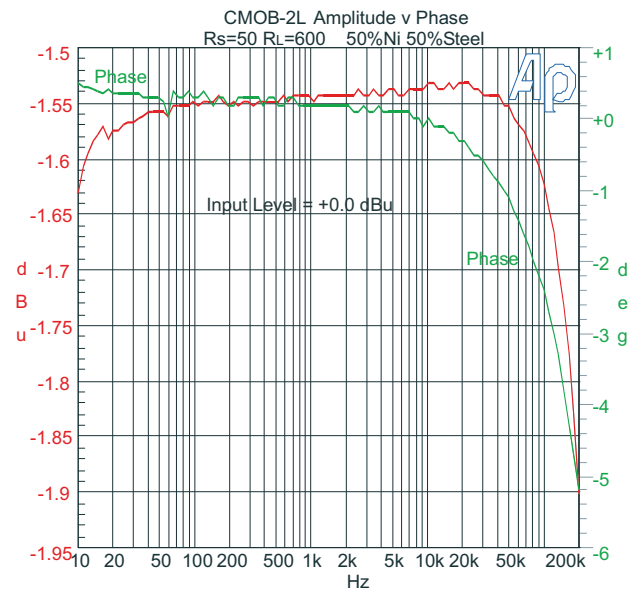
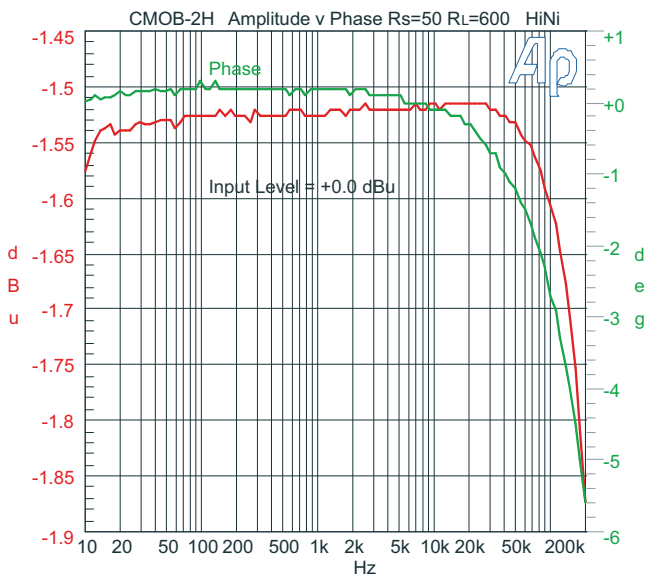
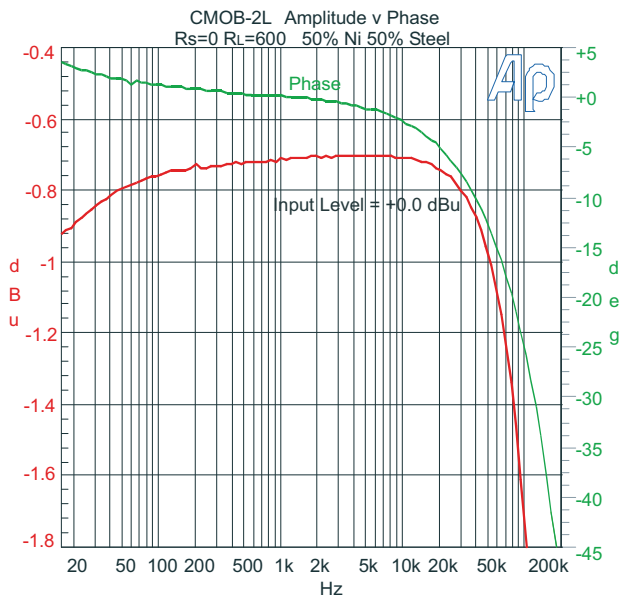
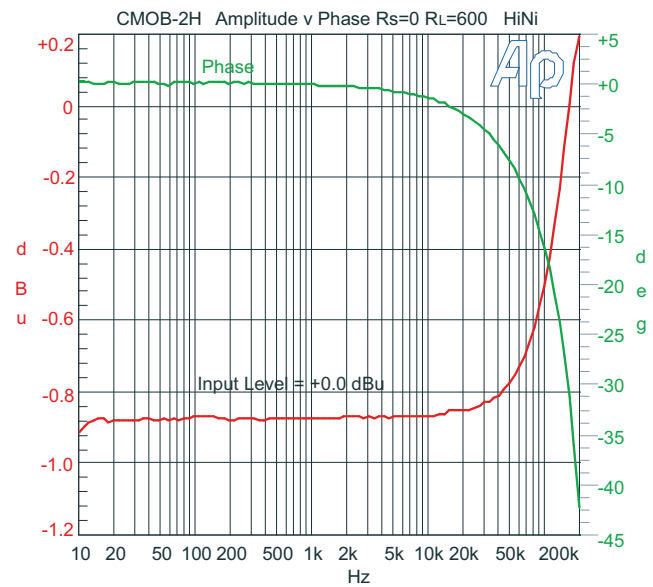
LINE OUTPUT TRANSFORMER Bifilar Windings

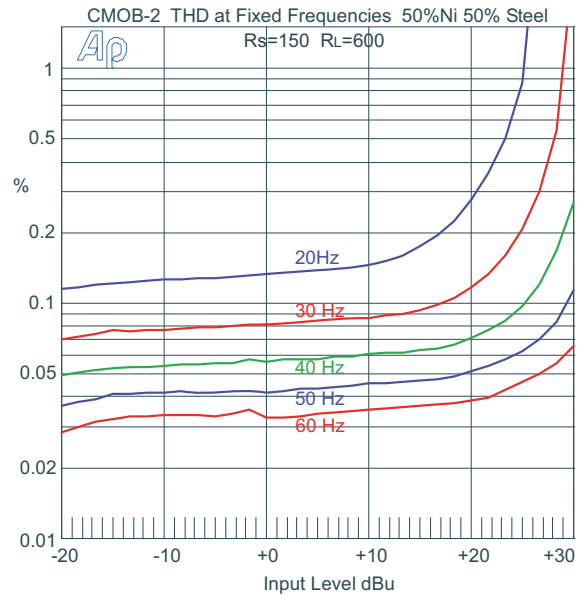
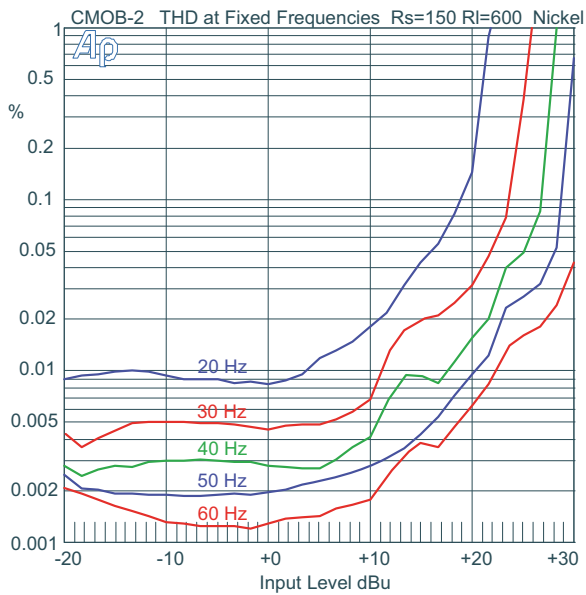
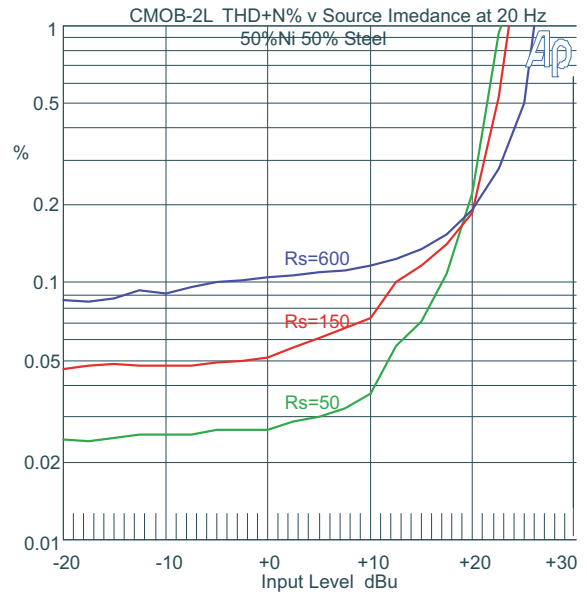
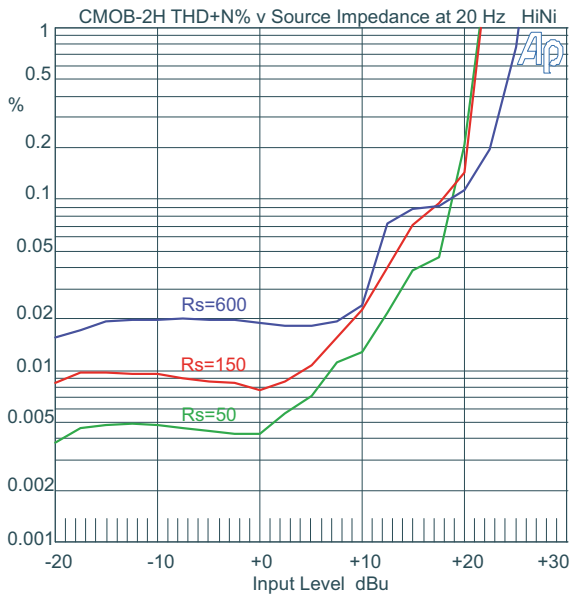
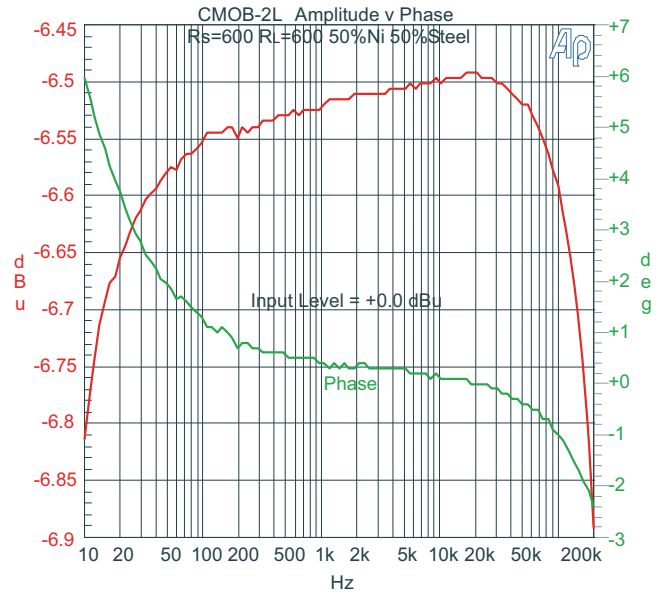
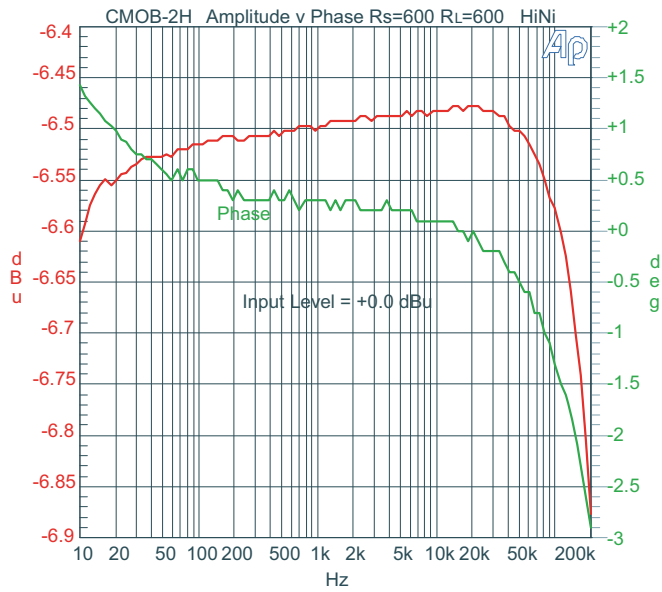
- Distortion 0.01% typ at 20 Hz, Rs=150 Ohms
- Excellent bandwidth -0.35 dB at 200 kHz
- Rs=150 Ohms 80% Nickel ("HighNickel") laminations
- +21 dBm at 20 Hz, 1% THD+N Rs≤150 Ohms
- Phase Shift -0.6° at 20 kHz, Rs=150 Ohms
- Low insertion loss

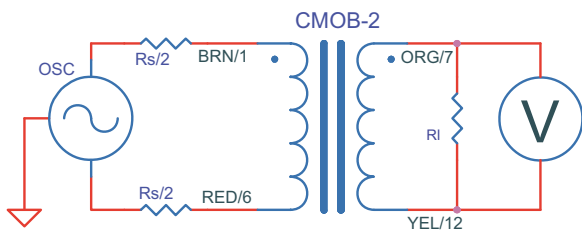
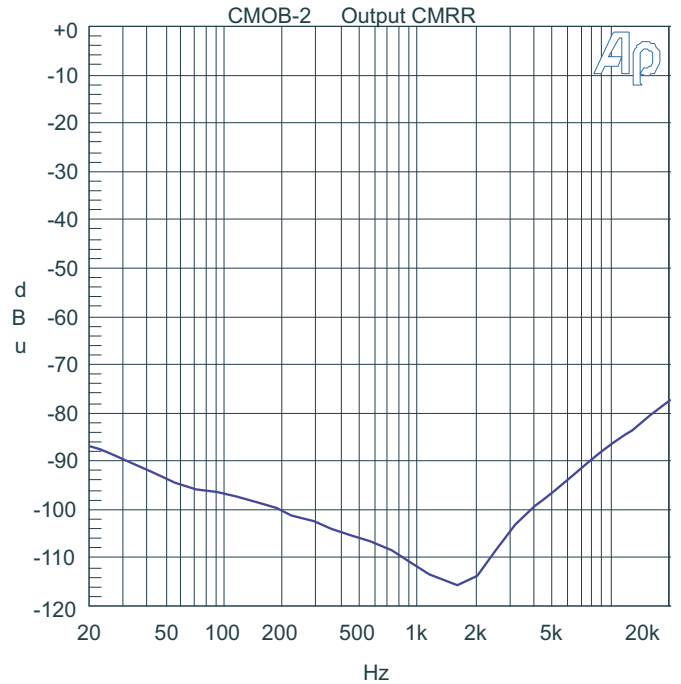
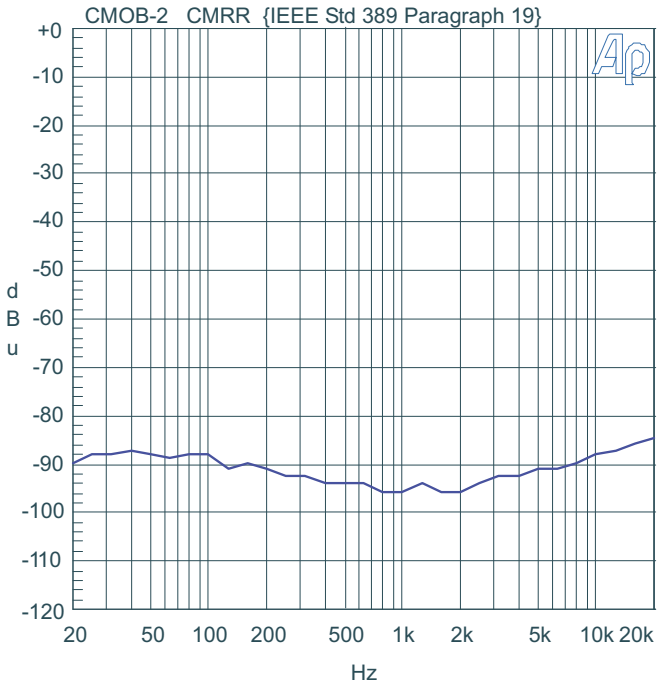
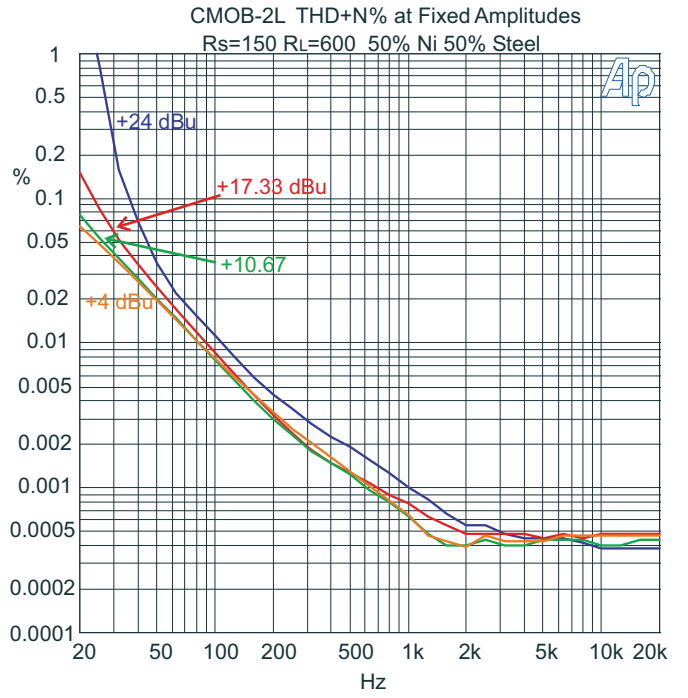
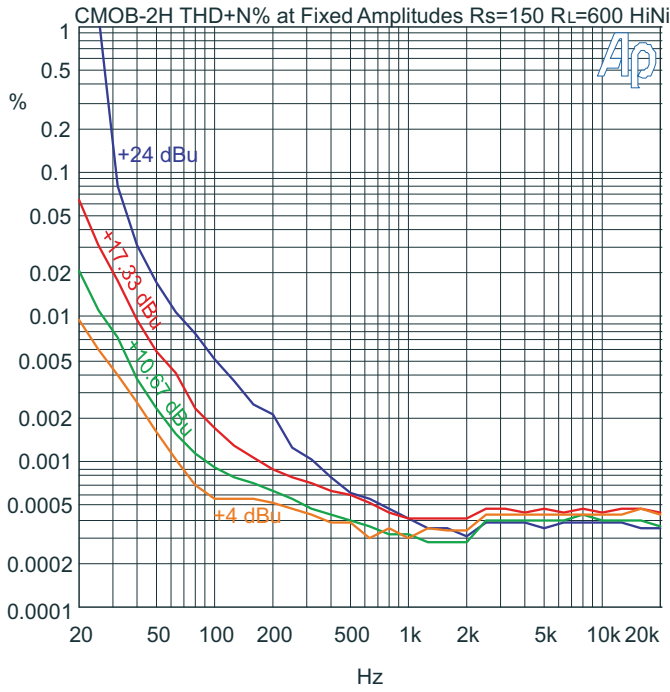
The CMOB-2 output transformer uses bifilar construction techniques. This two winding transformer delivers good coupling between windings providing very wide bandwidth. It is available with 80% nickel alloy ("H" suffix), 50% nickel + 50% steel ("L"), or all steel ("S"). It can be driven with source impedances of up to 600 Ohms. As with all line driving transformers the amplifier feeding it should be capable of cleanly delivering the power required to reach maximum operating level.

CMOB-2H / CMOB-2L / CMOB-2S

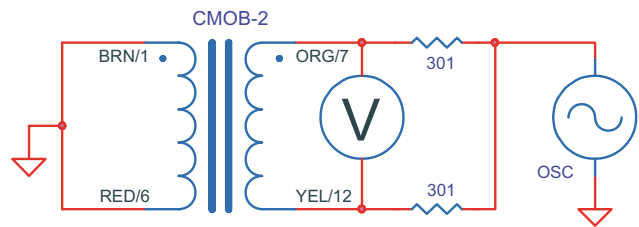
Parameter	Conditions	Typ
Turns Ratio		1 : 1.00
Input Impedance, Zi	20 Hz to 20 kHz, 0 dBu Test Circuit 3	680 Ohms
Voltage Gain	1 kHz HiNi Core, Rs=0 Test Circuit 1	-0.85 dB
	1 kHz 50% Nickel/50% Steel Core, Rs=0	-0.70 dB
Distortion (THD+N%)	1 kHz, +4 dBu, Rs=150 HiNi Test Circuit 1	0.0004%
	1 kHz, +4 dBu, Rs=150 50%Ni/50% Steel	0.0006%
Max 20 Hz input level	1.0% THD+N, Rs≤150 HiNi Test Circuit 1	+21 dB
	1.0% THD+N, Rs≤150 50% Ni 50% Steel	+22 dB
Response, ref 1 kHz	20 Hz Rs=150S HiNi Test Circuit 1	-0.08 dB
	20 kHz Rs=150S HiNi Test Circuit 1	+0.01 dB
	200 kHz Rs=150S HiNi Test Circuit 1	-0.35 dB
Phase Shift at 20Hz Phase Shift at 20 kHz	Referenced to source generator	+2°
	Test Circuit 1	-0.4°
CMRR	60 Hz Test Circuit 4 per IEEE Std 389-1996 ¶19	88 dB
	1 kHz Test Circuit 4 per IEEE Std 389-1996 ¶19	95 dB
Output CMRR	60 Hz Test Circuit 2	95 dB
	1 kHz Test Circuit 2	112 dB
Operating Temp Range	Operation and storage	0 C Min 70 C Max



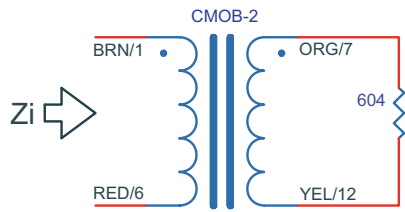




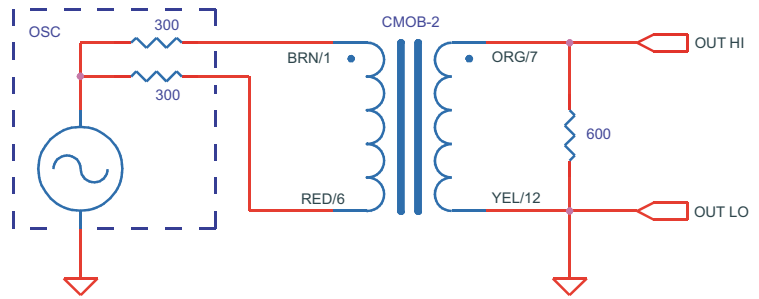
TEST CIRCUIT 1



TEST CIRCUIT 2



TEST CIRCUIT 3



TEST CIRCUIT 4

NOTES:

1. All graphs generated from one (1) randomly chosen device. No statistical averaging or weighting. Data from one sweep.
2. $R_L = 604$ unless otherwise noted.

